SPECIFICATION

SPEC. No. A-Serial-a D A T E : 2013 Sep.

То

Non-Controlled Copy

CUSTOMER'S PRODUCT NAME	TDK PRODUCT NAME MULTILAYER CERAMIC CHIP CAPACITORS CEU Series / Automotive Grade
	Serial Design

Please return this specification to TDK representatives.

If orders are placed without returned specification, please allow us to judge that specification is accepted by your side.

RECEIPT CONFIRMATION

DATE:	YEAR	MONTH	DAY

TDK Corporation Sales Electronic Components Sales & Marketing Group TDK-EPC Corporation Engineering Ceramic Capacitors Business Group

APPROVED	Person in charge	APPROVED	CHECKED	Person in charge

1. SCOPE

This specification is applicable to chip type multilayer ceramic capacitors with a priority over the other relevant specifications.

Production places defined in this specification shall be TDK-EPC Corporation Japan, TDK (Suzhou) Co., Ltd and TDK Components U.S.A. Inc.

EXPLANATORY NOTE:

This specification warrants the quality of the ceramic chip capacitors. The chips should be evaluated or confirmed a state of mounted on your product.

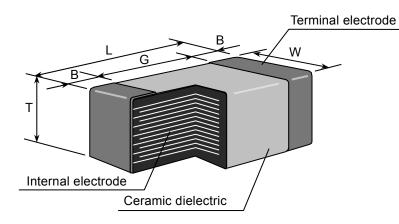
If the use of the chips goes beyond the bounds of the specification, we can not afford to guarantee.

2. CODE CONSTRUCTION

(Example)

Catalog Number :	<u>CEU3</u>	<u>E</u>	<u>2</u>	<u>X7R</u>	<u>1H</u>	<u>223</u>	<u>K</u>	<u>080</u>	<u>A</u> <u>E</u>
(Web)	(1)	(2)	(3)	(4)	(5)	(6)	(7)	(8)	(9) (10)
Item Description :	<u>CEU3</u> (1)	<u>E</u> (2)	<u>2</u> (3)	<u>X7R</u> (4)	<u>1H</u> (5)	<u>223</u> (6)	<u>K</u> (7)	<u> </u>	<u> </u>





Please refer to product list for the dimension of each product.

(2) Thickness

Symbol	Thickness
E	0.80 mm
J	1.25 mm

(3) Guaranteed life test condition	Symbol	Condition
(Details are shown in table 1 No.15 at page 7)	2	2 x Rated voltage

(4) Temperature Characteristics (Details are shown in table 1 No.6 at page 4)



(5) Rated Voltage

Symbol	Rated Voltage
2 A	DC 100V
1 H	DC 50 V

(6) Rated Capacitance

Stated in three digits and in units of pico farads (pF).

The first and Second digits identify the first and second significant figures of the capacitance, the third digit identifies the multiplier.

R is designated for a decimal point.

Example 223 \rightarrow 22,000pF (0.022nF)

(7) Capacitance tolerance

Symbol	Tolerance
К	± 10 %
М	± 20 %

(8) Thickness code (Only Catalog Number)

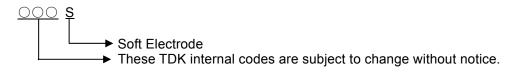
(9) Package code (Only Catalog Number)

(10) Special code (Only Catalog Number)

(11) Packaging (Only Item Description)

Symbol	Packaging
В	Bulk
Т	Taping

(12) TDK Internal code





3. OPERATING TEMPERATURE RANGE

T.C.	Min. operating	Max. operating	Reference
	Temperature	Temperature	Temperature
X7R	-55°C	125°C	25°C

4. STORING CONDITION AND TERM

5 to 40°C at 20 to 70%RH 6 months Max.

5. INDUSTRIAL WASTE DISPOSAL

Dispose this product as industrial waste in accordance with the Industrial Waste Law.



6. PERFORMANCE

No.	Item	Performance		Те	est or inspect	tion method
1	External Appearance	No defects which may aff performance.	ect	Inspect wi	th magnifying	g glass (3×).
2	Insulation Resistance	10,000MΩ or 500MΩ·µF whichever smaller.	min.	Apply rate	d voltage for	60s.
3	Voltage Proof	Withstand test voltage wi insulation breakdown or o damage.		Above DC 1 to 5s.	lischarge cur	ge I be applied for rent shall not
4	Capacitance	Within the specified toler	ance.	Measuring frequency Measuring		Measuring voltage
				1kF	lz±10%	1.0±0.2Vrms.
5	Dissipation Factor	T.C. D.F. X7R 0.03 max.		See No.4 condition.	in this table f	or measuring
6	Temperature Characteristics of Capacitance	Capacitance Change (%) No voltage applied X7R : ±15		steps show	wn in the follo	neasured by the owing table after obtained for each
				-	culated ref. S	TEP3 reading
				Step	Temper	rature(°C)
				1		5±2
				2		5±2
				3		5±2
				4	12	25±2



No.	Item	Performance	Test or inspection method
7	Robustness of	No sign of termination coming off,	Reflow solder the capacitors on a
	Terminations	breakage of ceramic, or other	P.C.Board shown in Appendix 1 and
		abnormal signs.	apply a pushing force of 17.7N with
			10±1s.
			Capacitor P.C.Board
8	Bending	No mechanical damage.	Reflow solder the capacitors on
			a P.C.Board shown in Appendix 2 and
			bend it for 5mm.
			$50 \xrightarrow{20}$ F R230 $45 \xrightarrow{45}$ $45 \xrightarrow{5}$
			(Unit : mm)
9	Solderability	New solder to cover over 75% of	Completely soak both terminations in
		termination.	solder at 235±5°C for 2±0.5s.
		25% may have pin holes or rough spots but not concentrated in one spot.	Solder : H63A (JIS Z 3282)
		Ceramic surface of A sections	Flux : Isopropyl alcohol (JIS K 8839)
		shall not be exposed due to	Rosin(JIS K 5902) 25% solid
		melting or shifting of termination material.	solution.
		A section	



No.	lte	em	Perfo	rmance		Test or inspection r	nethod	
10	Resistance to solder	External appearance		all be covered at		Completely soak both terminations in solder at 260±5°C for 5±1s.		
	heat	Capacitance	least 60% with new solder.			Preheating condition Temp. : 150±10°C		
			Characteristics	Change from the value before test		Time : 1 to 2min.		
			X7R	± 7.5 %		sopropyl alcohol (JIS Rosin (JIS K 5902) 2 solution.	,	
		D.F.	Meet the initial	spec.	Solder	: H63A (JIS Z 3282))	
		Insulation Resistance	Meet the initial s	spec.		the capacitors in am on for 24±2h before		
		Voltage proof	No insulation breakdown or other damage.					
11	Vibration	External appearance	No mechanical damage.			Reflow solder the capacitors on a P.C.Board shown in Appendix 1before		
		Capacitance	Characteristics	Change from the value before test	- Vibrate the capacitors with followir		h following	
			X7R	± 7.5 %				
	D.F. Mee		Meet the initial spec.		Duration : 20 min. Cycle : 12 cycles			
12	Temperature cycle	External appearance	No mechanical damage.		Reflow solder the capacitors on a P.C.Board shown in Appendix 1 before			
		Capacitance			testing.			
			Characteristics	Change from the value before test	•	Expose the capacitors in the co step1 through step 4 and repea		
			X7R	± 7.5 %	times o	consecutively.		
		D.F.	Meet the initial s	spec.	Leave the capacitors in ambient condition for 24±2h before measurement.		bient	
		Insulation Resistance	Meet the initial s	spec.	Step	Temperature(°C)	Time (min.)	
		Voltage	No insulation br	eakdown or	1	-55±3	30 ± 3	
		proof	other damage.		2	25±2	2 - 5	
					3	125±2	30 ± 2	
					4	25±2	2 - 5	



No.	lt	em	Perf	ormance	Test or inspection method	
13	Moisture Resistance (Steady State)	External appearance Capacitance	No mechanical Characteristics X7R	damage. Change from the value before test ± 12.5 %	Reflow solder the capacitors on a P.C.Board shown in Appendix 1 before testing. Leave at temperature 40±2°C, 90 to 95%RH for 500 +24,0h.	
		D.F. Insulation Resistance	Characteristics X7R : 200% of initial spec. max 1,000MΩ or 50MΩ· μ F min. whichever smaller.		Leave the capacitors in ambient condition for 24±2h before measurement.	
14	Moisture Resistance	External appearance Capacitance	No mechanical damage.		Reflow solder the capacitors on a P.C.Board shown in Appendix 1 befor testing.	
			Characteristics X7R	Change from the value before test ± 12.5 %	Apply the rated voltage at temperature 85°C and 85%RH for 1,000 +24,0h. Charge/discharge current shall not	
		D.F.	Characteristics X7R : 200% of initial spec. max 500MΩ or $25M\Omega \cdot \mu F$ min. whichever smaller.		exceed 50mA. Leave the capacitors in ambient condition for or 24±2h before	
		Insulation Resistance			measurement. Voltage conditioning Voltage treat the capacitors under testing temperature and voltage for 1 hour. Leave the capacitors in ambient condition for 24±2h before measurement. Use this measurement for initial value.	

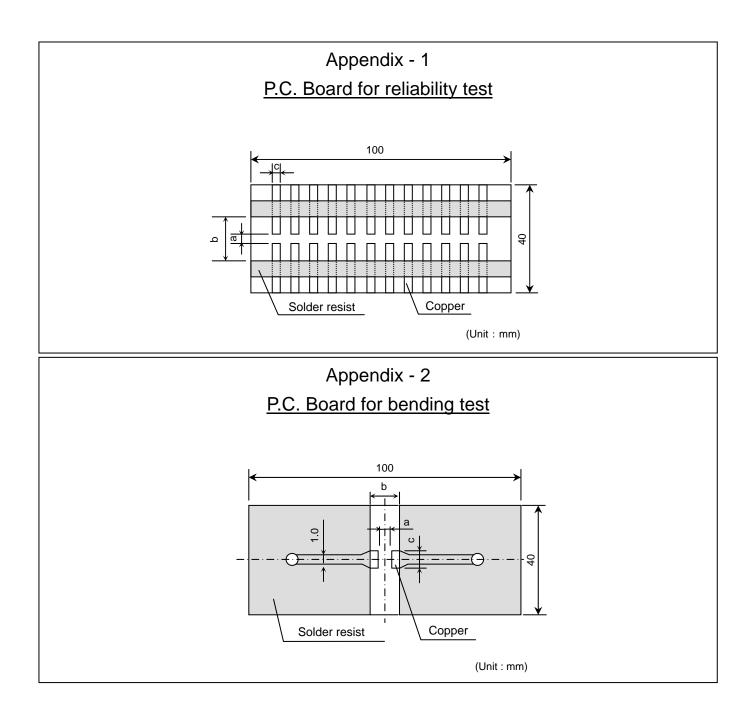


No.	Ite	em	Perfe	ormance	Test or inspection method
15	Life	External appearance	No mechanical damage.		Reflow solder the capacitors on a P.C.Board shown in Appendix 1 before testing.
		Capacitance	Characteristics	Change from the value before test	Below the voltage shall be applied at
			X7R	± 15 %	125±2°C for 1,000 +48, 0h. Applied voltage
					Rated voltage x2
	D.F. Characteristics X7R : 200% of initial spec. max		f initial spec. max	Charge/discharge current shall not exceed 50mA.	
		Insulation Resistance	1,000MΩ or 50MΩ·µF min. whichever smaller.		Leave the capacitors in ambient condition for 24±2h before measurement.
					Voltage conditioning Voltage treat the capacitors under testing temperature and voltage for 1 hour. Leave the capacitors in ambient condition for 24±2h before measurement. Use this measurement for initial value.

*As for the initial measurement of capacitors on number 8,12,13,14 and 15, leave capacitors at

150 –10,0°C for 1 hour and measure the value after leaving capacitors for 24±2h in ambient condition.





Material : Glass Epoxy (As per JIS C6484 GE4)

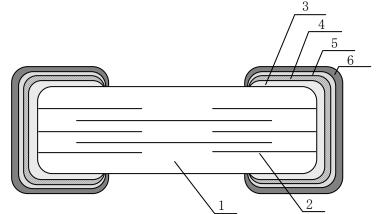
P.C. Board thickness : Appendix-1, 2 1.6mm

	Dimensions (mm)			
TDK (EIA style)	а	b	С	
CEU3 (CC0603)	1.0	3.0	1.2	
CEU4 (CC0805)	1.2	4.0	1.65	

Copper (thickness 0.035mm) Solder resist

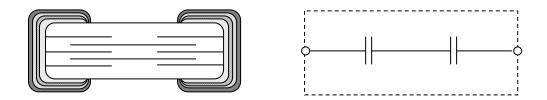


7. INSIDE STRUCTURE AND MATERIAL



No.	NAME MATERIAL	
1	Dielectric	BaTiO ₃
2	Electrode	Nickel (Ni)
3		Copper (Cu)
4	Termination	Conductive resin (Filler : Ag)
5	remination	Nickel (Ni)
6	Tin (Sn)	

8. EQUIVALENT CIRCUIT DIAGRAM



By applying inner electrode patterns divided, this product has the construction which is equivalent to 2 capacitors connected in series. When one side of the serial construction is broken, it helps to reduce the risk of short circuits.

Additionally, soft electrode is applied for the termination. It exhibits a high durability to mechanical stress such as board bending and helps to reduce the risk of short circuits as a result.

This product was developed for a design concept in order to decrease number of short circuits occurrence.

It is not to guarantee the performance to absolutely avoid short circuits.



9. Caution

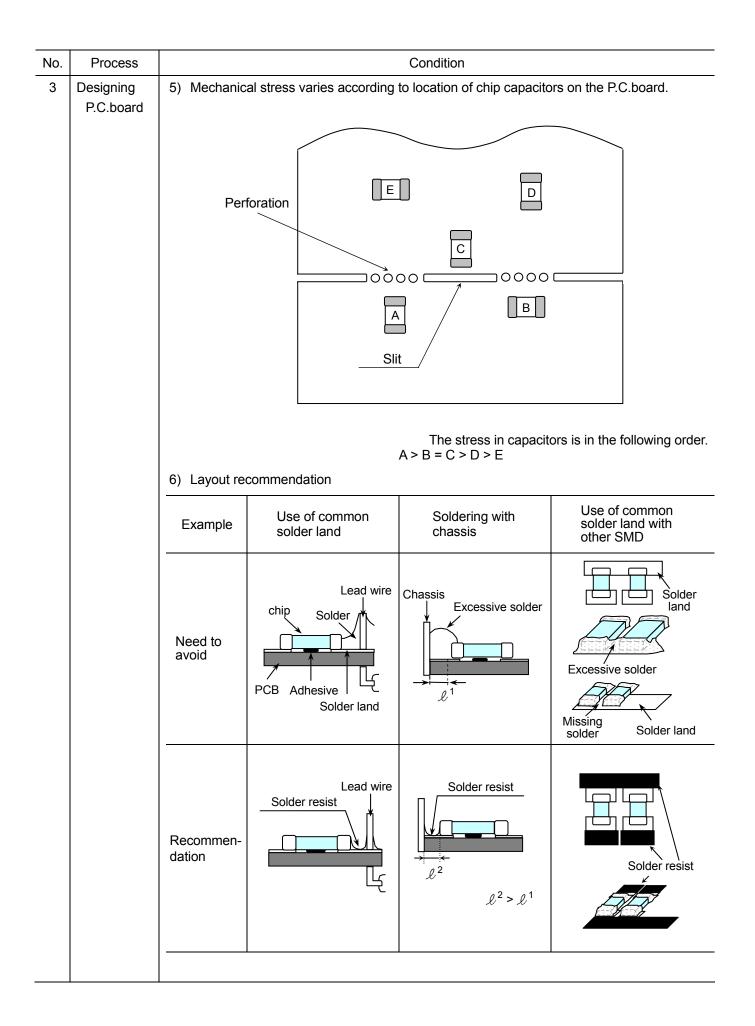
No.	Process	Condition
1	Operating Condition (Storage,	 1-1. Storage 1) The capacitors must be stored in an ambient temperature of 5 to 40°C with a relative humidity of 20 to 70%RH. The products should be used within 6 months upon receipt.
	Transportation)	2) The capacitors must be operated and stored in an environment free of dew condensation and these gases such as Hydrogen Sulphide, Hydrogen Sulphate, Chlorine, Ammonia and sulfur.
		3) Avoid storing in sun light and falling of dew.
		4) Do not use capacitors under high humidity and high and low atmospheric pressure which may affect capacitors reliability.
		5) Capacitors should be tested for the solderability when they are stored for long time.
		1-2. Handling in transportation
		In case of the transportation of the capacitors, the performance of the capacitors may be deteriorated depending on the transportation condition. (Refer to JEITA RCR-2335B 9.2 Handling in transportation)
2	Circuit design	 2-1. Operating temperature Operating temperature should be followed strictly within this specification, especially be careful with maximum temperature. 1) Do not use capacitors above the maximum allowable operating temperature.
		2) Surface temperature including self heating should be below maximum operating
		temperature. (Due to dielectric loss, capacitors will heat itself when AC is applied. Especially at high frequencies around its SRF, the heat might be so extreme that it may damage itself or the product mounted on. Please design the circuit so that the maximum temperature of the capacitors including the self heating to be below the maximum allowable operating temperature. Temperature rise at capacitor surface shall be below 20°C)
		 The electrical characteristics of the capacitors will vary depending on the temperature. The capacitors should be selected and designed in taking the temperature into consideration. 2-2. Operating voltage Operating voltage across the terminals should be below the rated voltage.
		When AC and DC are super imposed, V_{0-P} must be below the rated voltage. (1) and (2)
		AC or pulse with overshooting, V_{P-P} must be below the rated voltage. (3), (4) and (5) When the voltage is started to apply to the circuit or it is stopped applying, the irregular voltage may be generated for a transit period because of resonance or switching. Be sure to use the capacitors within rated voltage containing these Irregular voltage.
		Voltage (1) DC voltage (2) DC+AC voltage (3) AC voltage
		Positional Measurement (Rated voltage)
		Voltage (4) Pulse voltage (A) (5) Pulse voltage (B)
		Positional Measurement (Rated voltage) $V_{P-P} \downarrow \downarrow$





No.	Process		Condition				
2	Circuit design <u>∧</u> Caution	 Even below the rated voltage, the reliability of the capacitors n 	if repetitive high frequency AC or pulse is applied hay be reduced.				
		 The effective capacitance will vary depending on applied DC and AC voltages. The capacitors should be selected and designed in taking the voltages into consideration. 					
		connected in series by having ir However, it does not guarante each side of the serial construct When one side of the serial con whatever, it is assumed that the to larger electric pressure.	e the performance mentioned on specification b				
		connected in series by one capa	t function which is equivalent to 2 capacitors acitor on automotive battery line. In the case of se 12V (or below,) battery line certainly.				
		capacitors may vibrate themse	are used in AC and/or pulse voltages, the lves and generate audible sound.				
3	Designing P.C.board	 The amount of solder at the terminations has a direct effect on the relia capacitors. 1) The greater the amount of solder, the higher the stress on the chip and the more likely that it will break. When designing a P.C.board, or shape and size of the solder lands to have proper amount of solder terminations. 					
		 Avoid using common solder land for multiple terminations and provide solder land for each terminations. 					
		3) Size and recommended land di	mensions.				
		Ch	ip capacitors Solder land				
			A Solder resist				
		Flow soldering	(mm)				
		Type CEU3 Symbol (CC0603)	CEU4 (CC0805)				
		A 0.7 – 1.0	1.0 – 1.3				
		B 0.8 – 1.0	1.0 – 1.2				
		C 0.6 – 0.8	0.8 – 1.1				
		Reflow soldering	(mm)				
		Type CEU3 Symbol (CC0603)	CEU4 (CC0805)				
		A 0.6 – 0.8	0.9 – 1.2				
		B 0.6 – 0.8	0.7 – 0.9				
		C 0.6 – 0.8	0.9 – 1.2				
	l	<u> </u>					
			-				
		⊗TDI	<				

Process			Condition		
Designing P.C.board	4)	Recommended	chip capacitors layout is as follo	wing.	
	_		Disadvantage against bending stress	Advantage against bending stress	
		Mounting face	Perforation or slit	Perforation or slit	
			Break P.C.board with mounted side up.	Break P.C.board with mounted side down.	
	-		Mount perpendicularly to perforation or slit	Mount in parallel with perforation or slit	
		Chip arrangement (Direction)	Perforation or slit	Perforation or slit	
	-		Closer to slit is higher stress	Away from slit is less stress	
		Distance from slit	$(\ell_1 < \ell_2)$	$\begin{pmatrix} \ell_2 \\ \vdots \\ \vdots \\ (\ell_1 < \ell_2) \end{pmatrix}$	
	Designing	Designing 4) P.C.board -	Designing P.C.board 4) Recommended Mounting face Mounting face Chip arrangement (Direction) Distance from	Designing 4) Recommended chip capacitors layout is as follo Pc.board Disadvantage against bending stress Mounting face Perforation or slit Mount error Break P.C.board with mounted side up. Mount perpendicularly to perforation or slit Chip arrangement (Direction) Perforation or slit Closer to slit is higher stress Distance from Left form	





No.	Process			Condition			
4	Mounting	 4-1. Stress from mounting head If the mounting head is adjusted too low, it may induce excessive stress in the chip capacitors to result in cracking. Please take following precautions. 1) Adjust the bottom dead center of the mounting head to reach on the P.C.board 					
		surface and not			* • • • • • •		
				ressure to be 1 to 3N	-		
			e bottom side	gy from mounting hear e of the P.C.board.	ad, it is important to provide		
			Not r	recommended	Recommended		
		Single sided mounting		Crack	Support pin		
		Double-sides mounting	Solder	Crack	Support pin		
		When the centering jaw is worn out, it may give mechanical impact on the capacitors to cause crack. Please control the close up dimension of the centering jaw and provide sufficient preventive maintenance and replacement of it.					
		4-2. Amount of adhe	esive				
		-			¥		
		-					
		_	E	xample : CEU4 (CC08	305)		
		_	а	0.2mm m	n.		
		-	b	70 - 100µ	m		
		-	С	Do not touch the s	solder land		



No.	Process		Co	ondition			
5	Soldering	Idering 5-1. Flux selection Although highly-activated flux gives better solderability, substances which increase activity may also degrade the insulation of the chip capacitors. To avoid such degradation, it is recommended following.					
		1) It is recommended to Strong flux is not reco	use a mildly ad	ctivated rosin f	lux (less than 0	.1wt% chlorine	
		2) Excessive flux must b	e avoided. Plea	se provide pro	per amount of fl	ux.	
		3) When water-soluble f	lux is used, eno	ugh washing is	necessary.		
		5-2. Recommended sold	ering profile by v	arious method	S		
		Wave sold	-		Reflow solde	-	
		Solder Preheating	Natural cooling	→	Preheating	ldering Natural coolin ←→	
		Peak		Peak			
		Temp G L E B D C C C C C C C C C C C C C C C C C C		Temp (°C)			
		Over 60 sec. →	Over 60 sec.	→ [°] < ^{Ove}	r 60 sec. Peak	←→ Temp time	
		Manual soldering					
		(Solde	r iron)				
		300 Ω U U U U U U U U U U U U U	3sec. (As short a	s possible)			
		5-3. Recommended sold	ering peak temp	and peak tem	o duration		
		Temp./Duration	Wave so	•	Reflow se	oldering	
		Solder	Peak temp(°C)	Duration(sec.)	Peak temp(°C)	Duration(sec.)	
		Sn-Pb Solder	250 max.	3 max.	230 max.	20 max.	
		Lead Free Solder	260 max.	5 max.	260 max.	10 max.	
		Recommended solde Sn-37Pb (Sn-Pb sol Sn-3.0Ag-0.5Cu (Le	der)		<u> </u>	<u> </u>	



lo.	Process	Condition					
5	Soldering	5-4. Avoiding thermal shock					
		1) Preheating condition					
		Soldering		Туре	Temp. (°C)		
		Wave soldering	g CEU3(CC0603), C	EU4(CC0805)	∆T ≤ 150		
		Reflow soldering	g CEU3(CC0603), C	EU4(CC0805)	∆T ≤ 150		
		Manual solderin	g CEU3(CC0603), C	EU4(CC0805)	∆T ≤ 150		
		cleaning, the temper 5-5. Amount of solder Excessive solder temperature char	rature difference (∆T) must be less tha r tensile force in It in chip cracking	dipped into a solvent n 100°C. n chip capacitors w g. In sufficient solder r		
		Excessive solder			her tensile force in capacitors to cause ck		
		Adequate		Maximum Minimum			
		Insufficient solder		cau	v robustness may se contact failure or capacitors come off P.C.board.		
		5-6. Solder repair by sold1) Selection of the sold					
		land size. The higher heat shock may cau Please make sure t time in accordance	er the tip temperature use a crack in the ch he tip temp. before s	e, the quicker the p capacitors. oldering and keep mended conditior	n. (Please preheat the		
		Recommended so	Ider iron condition (S	n-Pb Solder and	Lead Free Solder)		
		Temp. (°C)	Duration (sec.)	Wattage (W)	Shape (mm)		
		300 max.	3 max.	20 max.	Ø 3.0 max.		



No.	Process	Condition
5	Soldering	 Direct contact of the soldering iron with ceramic dielectric of chip capacitors may cause crack. Do not touch the ceramic dielectric and the terminations by solder iron.
		5-7. Sn-Zn solder
		Sn-Zn solder affects product reliability.
		Please contact TDK in advance when utilize Sn-Zn solder.
		5-8. Countermeasure for tombstone
		The misalignment between the mounted positions of the capacitors and the land
		patterns should be minimized. The tombstone phenomenon may occur especially
		the capacitors are mounted (in longitudinal direction) in the same direction of the reflow soldering.
		(Refer to JEITA RCR-2335B Annex 1 (Informative) Recommendations to prevent th
		tombstone phenomenon)
6	Cleaning	1) If an unsuitable cleaning fluid is used, flux residue or some foreign articles may
		stick to chip capacitors surface to deteriorate especially the insulation resistance.
		2) If cleaning condition is not suitable, it may damage the chip capacitors.
		2)-1. Insufficient washing
		(1) Terminal electrodes may corrode by Halogen in the flux.
		(2) Halogen in the flux may adhere on the surface of capacitors, and lower the
		insulation resistance.
		(3) Water soluble flux has higher tendency to have above mentioned
		problems (1) and (2).
		2)-2. Excessive washing
		When ultrasonic cleaning is used, excessively high ultrasonic energy output
		can affect the connection between the ceramic chip capacitor's body and the
		terminal electrode. To avoid this, following is the recommended condition.
		Power : 20 W/ & max.
		Frequency : 40 kHz max.
		Washing time : 5 minutes max.
		2)-3. If the cleaning fluid is contaminated, density of Halogen increases, and it may
		bring the same result as insufficient cleaning.



No.	Process	Condition						
7	Coating and molding of the P.C.board	2) Please ve emission						
8	Handling after chip mounted <u>A</u> Caution		Please pay attention not to bend or distort the P.C.board after soldering i otherwise the chip capacitors may crack.					
		 Bend Twist Bend Twist When functional check of the P.C.board is performed, check pin pressure tends to be adjusted higher for fear of loose contact. But if the pressure is excessive and bend the P.C.board, it may crack the chip capacitors or peel the terminations off. Please adjust the check pins not to bend the P.C.board. 						
		Item	Not recommended	Recommended				
		Board bending	Termination peeling Check pin	Support pin				
				1				



No.	Process	Condition			
9	Handling of loose chip capacitors	 If dropped the chip capacitors may crack. Once dropped do not use it. Especially, the large case sized chip capacitors are tendency to have cracks easily, so please handle with care. 			
		2) Piling the P.C.board after mounting for storage or handling, the corner of the P.C. board may hit the chip capacitors of another board to cause crack.			
10	Capacitance aging	The capacitors (Class 2) have aging in the capacitance. They may not be used in precision time constant circuit. In case of the time constant circuit, the evaluation should be done well.			
11	Estimated life and estimated failure rate of capacitors	As per the estimated life and the estimated failure rate depend on the temperature and the voltage. This can be calculated by the equation described in JEITA RCR-2335B Annex 6 (Informative) Calculation of the estimated lifetime and the estimated failure rate (Voltage acceleration coefficient : 3 multiplication rule, Temperature acceleration coefficient : 10°C rule) The failure rate can be decreased by reducing the temperature and the voltage but they will not be guaranteed.			



No.	Process	Condition
No. 12	Process Others ▲ Caution	Condition The products listed on this specification sheet are intended for use in general electronic equipment (AV equipment, telecommunications equipment, home appliances, amusement equipment, industrial robots) and automotive application under a normal operation and use condition. The products are not designed or warranted to meet the requirements of the applications listed below, whose performance and/or quality require a more stringent level of safety or reliability, or whose failure, malfunction or trouble could cause serious damage to society, person or property. Please understand that we are not responsible for any damage or liability caused by use of the products in any of the applications below or for any other use exceeding the range or conditions set forth in this specification sheet. If you intend to use the products in the applications listed below or if you have special requirements exceeding the range or conditions set forth in this specification, please contact us. (1) Aerospace/Aviation equipment (2) Transportation equipment (electric trains, ships, etc. except automotive application) (3) Medical equipment (3) Aedical equipment (4) Power-generation control equipment (3) Public information-processing equipment (1) Lister prevention control equipment (3) Public information-processing equipment (1) Disaster prevention/crime prevention equipment (3) Cher applications prevention equipment (1) Disaster prevention/crime prevention equipment (1) Disaster prevention/crime prevention equipment (1) Softer applications that are not considered general-purpose applications
		When designing your equipment even for general-purpose applications, you are kindly requested to take into consideration securing protection circuit/device or providing backup circuits in your equipment.



10. Packaging label

Packaging shall be done to protect the components from the damage during transportation and storing, and a label which has the following information shall be attached.

1) Inspection No.
 2) TDK P/N
 3) Customer's P/N
 4) Quantity

*Composition of Inspection No.

Example $\underline{M} \underline{2} \underline{A} - \underline{OO} - \underline{OOO}$ (a) (b) (c) (d) (e)

a) Line code

- b) Last digit of the year
- c) Month and A for January and B for February and so on. (Skip I)
- d) Inspection Date of the month.
- e) Serial No. of the day

11. Bulk packaging quantity

Total number of components in a plastic bag for bulk packaging: 1,000pcs.



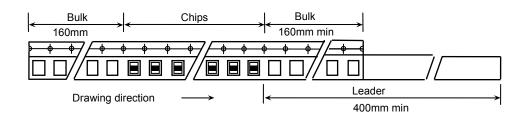
12. TAPE PACKAGING SPECIFICATION

1. CONSTRUCTION AND DIMENSION OF TAPING

1-1. Dimensions of carrier tape

Dimensions of paper tape shall be according to Appendix 3. Dimensions of plastic tape shall be according to Appendix 4.

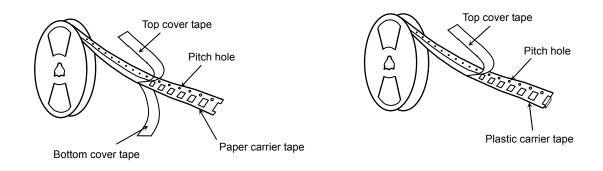
1-2. Bulk part and leader of taping



1-3. Dimensions of reel

Dimensions of Ø178 reel shall be according to Appendix 5. Dimensions of Ø330 reel shall be according to Appendix 6.

1-4. Structure of taping



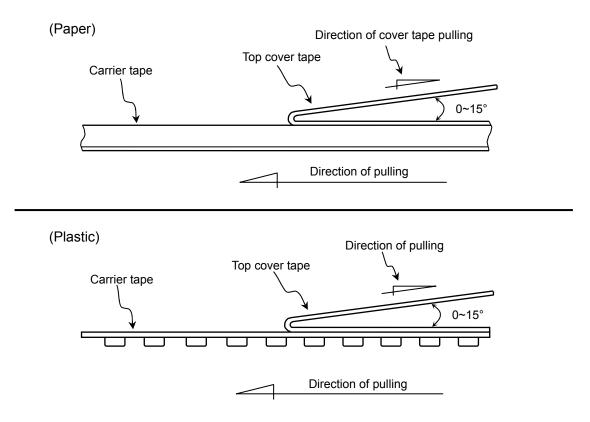
2. CHIP QUANTITY

Туре	Thickness	Taping	Chip quantity (pcs.)		
	of chip	Material	φ178mm reel	φ330mm reel	
CEU3	CEU3 0.80 mm Paper		4,000	10,000	
CEU4	1.25 mm	Plastic	2,000	10,000	



3. PERFORMANCE SPECIFICATIONS

3-1. Fixing peeling strength (top tape)0.05-0.7N. (See the following figure.)

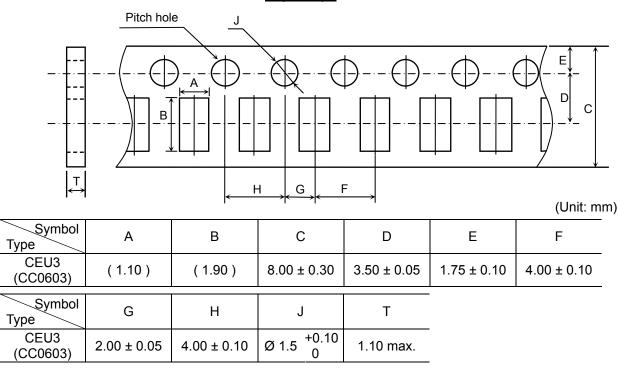


- 3-2. Carrier tape shall be flexible enough to be wound around a minimum radius of 30mm with components in tape.
- 3-3. The missing of components shall be less than 0.1%
- 3-4. Components shall not stick to fixing tape.
- 3-5. The fixing tapes shall not protrude beyond the edges of the carrier tape not shall cover the sprocket holes.



Appendix 3

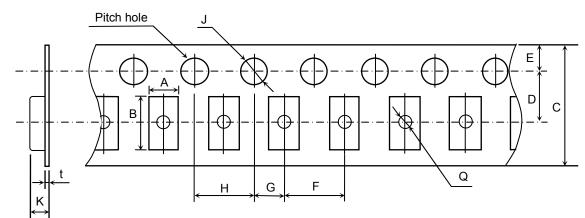




* The values in the parentheses () are for reference.

Appendix 4

Plastic Tape



(Unit: mm)

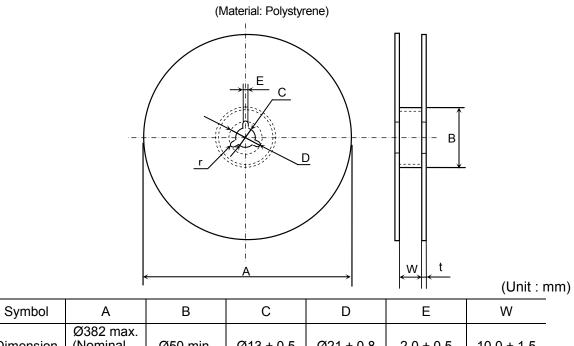
Symbol Type	А	В	С	D	E	F
CEU4 (CC0805)	(1.50)	(2.30)	8.00 ± 0.30	3.50 ± 0.05	1.75 ± 0.10	4.00 ± 0.10
Symbol Type	G	Н	J	К	t	Q
CEU4 (CC0805)	2.00 ± 0.05	4.00 ± 0.10	Ø 1.5 +0.10 0	2.50 max.	0.30 max.	Ø 0.50 min.

* The values in the parentheses () are for reference.



			ppendi: eria : Polystyrend	e)		∽ ∽
Symbol	А	В	С	D	E	W ₁
Dimension	Ø178 ± 2.0	Ø60 ± 2.0	Ø13 ± 0.5	Ø21 ± 0.8	2.0 ± 0.5	9.0 ± 0.3
Symbol	W ₂	r				
Dimension	13.0 ± 1.4	1.0				

Appendix 6



Dimension	Ø382 max. (Nominal Ø330)	Ø50 min.	Ø13 ± 0.5	Ø21 ± 0.8	2.0 ± 0.5	10.0 ± 1.5
Symbol	t	r				
Dimension	0.0.1.0.5	4.0				
Dimension	2.0 ± 0.5	1.0				
-	1		-			



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